Emile Albert Schweikert

List of Publications by Year
in descending order

221 papers	3,058 citations	279798 23 h-index	254184 43 g-index
229 all docs	229 docs citations	229 times ranked	2126 citing authors

#	Article	IF	Citations
1	New Methodology for Accurate Determination of Molecular Co-localization at the Nanoscale. Langmuir, 2022, 38, 5626-5632.	3.5	2
2	Topological Design of Highly Anisotropic Aligned Hole Transporting Molecular Bottlebrushes for Solution-Processed OLEDs. Journal of the American Chemical Society, 2022, 144, 8084-8095.	13.7	10
3	Nanoprojectile Secondary Ion Mass Spectrometry for Nanometrology of Nanoparticles and Their Interfaces. Analytical Chemistry, 2022, 94, 7868-7876.	6.5	4
4	Nanoprojectile Secondary Ion Mass Spectrometry for Analysis of Extracellular Vesicles. Analytical Chemistry, 2021, 93, 7481-7490.	6.5	13
5	Nanoparticle-Enabled Multiplexed Electrochemical Immunoassay for Detection of Surface Proteins on Extracellular Vesicles. ACS Applied Materials & Interfaces, 2021, 13, 52321-52332.	8.0	13
6	Enhanced sputter and secondary ion yields using MeV gold nanoparticle beams delivered by the Andromede facility. Journal of Vacuum Science and Technology B:Nanotechnology and Microelectronics, 2020, 38, 044008.	1.2	2
7	Hypervelocity cluster ion impacts on free standing graphene: Experiment, theory, and applications. Journal of Chemical Physics, 2019, 150, 160901.	3.0	10
8	Label Free Particle-by-Particle Quantification of DNA Loading on Sorted Gold Nanostars. Analytical Chemistry, 2019, 91, 5566-5572.	6.5	16
9	Nanoscale molecular analysis of photoresist films with massive cluster secondary-ion mass spectrometry. Journal of Micro/ Nanolithography, MEMS, and MOEMS, 2019, 18, 1.	0.9	4
10	Understanding photoacid generator distribution at the nanoscale using massive cluster secondary ion mass spectrometry. Journal of Micro/ Nanolithography, MEMS, and MOEMS, 2019, 18, 1.	0.9	5
11	Understanding the photoacid generator distribution at nanoscale using massive cluster secondary ion mass spectrometry. , 2019, , .		1
12	Nano-scale molecular analysis of photo-resist films with massive cluster secondary ion mass spectrometry. , 2019, , .		0
13	10.1063/1.5080606.1. , 2019, , .		0
14	10.1063/1.5080606.4. , 2019, , .		0
15	â€œTrampolineâ€•ejection of organic molecules from graphene and graphite via keV cluster ions impacts. Journal of Chemical Physics, 2018, 148, 144309.	3.0	5
16	Fluoropolymer-diluted small molecule organic semiconductors with extreme thermal stability. Applied Physics Letters, 2018, 113, .	3.3	13
17	Molecular Colocalization Using Massive Gold Cluster Secondary Ion Mass Spectrometry. Analytical Chemistry, 2018, 90, 12692-12697.	6.5	11
18	The influence of surface chemistry on the kinetics and thermodynamics of bacterial adhesion. Scientific Reports, 2018, 8, 17247.	3.3	124

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19	2D AlB2 flakes for epitaxial thin film growth. Journal of Materials Research, 2018, 33, 2318-2326.	2.6	6
20	The collision of a hypervelocity massive projectile with free-standing graphene: Investigation of secondary ion emission and projectile fragmentation. Journal of Chemical Physics, 2017, 146, 054305.	3.0	11
21	Ejection-ionization of molecules from free standing graphene. Journal of Chemical Physics, 2017, 146, 084308.	3.0	8
22	Characterization of nanometric inclusions via nanoprojectile impacts. Journal of Vacuum Science and Technology B:Nanotechnology and Microelectronics, 2016, 34, .	1.2	3
23	Characterization of individual free-standing nano-objects by cluster SIMS in transmission. Journal of Vacuum Science and Technology B:Nanotechnology and Microelectronics, 2016, 34, 03H117.	1.2	5
24	SIMS of transfer ribonucleic acid molecules encapsulated between free-standing graphene sheets. Biointerphases, 2016, 11, 02A324.	1.6	1
25	Testing Molecular Homogeneity at the Nanoscale with Massive Cluster Secondary Ion Mass Spectrometry. Analytical Chemistry, 2016, 88, 7639-7646.	6.5	17
26	Advanced photoresist technologies by intricate molecular brush architectures: Diblock brush terpolymerâ€based positiveâ€tone photoresist materials. Journal of Polymer Science Part A, 2015, 53, 193-199.	2.3	12
27	Single impacts of keV fullerene ions on free standing graphene: Emission of ions and electrons from confined volume. Journal of Chemical Physics, 2015, 143, 164302.	3.0	17
28	Nanodomain analysis with clusterâ€SIMS: application to the characterization of macromolecular brush architecture. Surface and Interface Analysis, 2015, 47, 1051-1055.	1.8	2
29	Mass Spectrometry of Nanoparticles is Different. Journal of the American Society for Mass Spectrometry, 2015, 26, 1259-1265.	2.8	10
30	Hypervelocity nanoparticle impacts on free-standing graphene: A sui generis mode of sputtering. Journal of Chemical Physics, 2015, 142, 044308.	3.0	17
31	Directing Selfâ€Assembly of Nanoscopic Cylindrical Diblock Brush Terpolymers into Films with Desired Spatial Orientations: Expansion of Chemical Composition Scope. Macromolecular Rapid Communications, 2014, 35, 437-441.	3.9	20
32	SIMS methodology for probing the fate and dispersion of catalytically active molecules. International Journal of Mass Spectrometry, 2014, 370, 107-113.	1.5	5
33	Preventing adhesion of Escherichia coli O157:H7 and Salmonella Typhimurium LT2 on tomato surfaces via ultrathin polyethylene glycol film. International Journal of Food Microbiology, 2014, 185, 73-81.	4.7	25
34	Surface characterization of biological nanodomains using NPâ€ToFâ€SIMS. Surface and Interface Analysis, 2013, 45, 294-297.	1.8	4
35	Simultaneous detection and localization of secondary ions and electrons from single large cluster impacts. Surface and Interface Analysis, 2013, 45, 529-531.	1.8	1
36	Characteristics of positive and negative secondary ions emitted from Au₃⁺ and Au₄₀₀⁺⁴ impacts. Surface and Interface Analysis, 2013, 45, 134-137.	1.8	10

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37	Characterization of individual nano-objects with nanoprojectile-SIMS. Surface and Interface Analysis, 2013, 45, 329-332.	1.8	3
38	Metal-assisted SIMS with hypervelocity gold cluster projectiles. International Journal of Mass Spectrometry, 2013, 343-344, 28-36.	1.5	11
39	Size-dependent emission of negative ions from gold nanoparticles bombarded with C60 and Au400. International Journal of Mass Spectrometry, 2013, 334, 43-48.	1.5	18
40	Nanoscopic Cylindrical Dual Concentric and Lengthwise Block Brush Terpolymers as Covalent Preassembled High-Resolution and High-Sensitivity Negative-Tone Photoresist Materials. Journal of the American Chemical Society, 2013, 135, 4203-4206.	13.7	104
41	Measuring the internal energies of species emitted from hypervelocity nanoprojectile impacts on surfaces using recalibrated benzylpyridinium probe ions. Journal of Chemical Physics, 2013, 138, 214301.	3.0	17
42	Bottom-up/top-down high resolution, high throughput lithography using vertically assembled block bottle brush polymers. , 2013, , .		0
43	Bottom-up/top-down, high-resolution, high-throughput lithography using vertically assembled block bottle brush polymers. Journal of Micro/ Nanolithography, MEMS, and MOEMS, 2013, 12, 043006.	0.9	10
44	Bidirectional Ion Emission from Massive Gold Cluster Impacts on Nanometric Carbon Foils. Journal of Physical Chemistry C, 2012, 116, 8138-8144.	3.1	9
45	Noradrenaline-Functionalized Hyperbranched Fluoropolymerâ€“Poly(ethylene glycol) Cross-Linked Networks As Dual-Mode, Anti-Biofouling Coatings. ACS Nano, 2012, 6, 1503-1512.	14.6	52
46	Analysis of Fluorescent Proteins with a Nanoparticle Probe. Journal of Physical Chemistry Letters, 2012, 3, 337-341.	4.6	1
47	Targeted surface nanocomplexity: two-dimensional control over the composition, physical properties and anti-biofouling performance of hyperbranched fluoropolymerâ€“poly(ethylene glycol) amphiphilic crosslinked networks. Polymer Chemistry, 2012, 3, 3121.	3.9	36
48	On the surface mapping using individual cluster impacts. Nuclear Instruments & Methods in Physics Research B, 2012, 273, 270-273.	1.4	7
49	Electrochemical release of hepatocyte-on-hydrogel microstructures from ITO substrates. Analytical and Bioanalytical Chemistry, 2012, 402, 1847-1856.	3.7	11
50	Analysis of Native Biological Surfaces Using a 100 kV Massive Gold Cluster Source. Analytical Chemistry, 2011, 83, 8448-8453.	6.5	27
51	Quantitative Label-Free Characterization of Avidinâ€“Biotin Assemblies on Silanized Glass. Analytical Chemistry, 2011, 83, 7173-7178.	6.5	15
52	Probing chemical homogeneity within single cluster impact sites. Surface and Interface Analysis, 2011, 43, 551-554.	1.8	2
53	Characterization and quantification of biological micropatterns using cluster SIMS. Surface and Interface Analysis, 2011, 43, 555-558.	1.8	11
54	Realâ€time localization of single C₆₀ impacts with correlated secondary ion detection. Surface and Interface Analysis, 2011, 43, 484-487.	1.8	7

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55	Massive clusters: Secondary emission from qkeV to qMeV. New emission processes? New SIMS probe?. Surface and Interface Analysis, 2011, 43, 62-65.	1.8	12
56	The Pegase project, a new solid surface probe: focused massive cluster ion beams. Surface and Interface Analysis, 2011, 43, 66-69.	1.8	21
57	Examination of individual nanoparticles with cluster SIMS. Surface and Interface Analysis, 2011, 43, 547-550.	1.8	3
58	Statistics of electron and ion emission from single massive cluster impacts. Surface and Interface Analysis, 2011, 43, 49-52.	1.8	3
59	Photon emission from massive projectile impacts on solids. Surface and Interface Analysis, 2011, 43, 53-57.	1.8	6
60	The use of glass substrates with bi-functional silanes for designing micropatterned cell-secreted cytokine immunoassays. Biomaterials, 2011, 32, 5478-5488.	11.4	24
61	Characterization and quantification of nanoparticleâ€“antibody conjugates on cells using C60 ToF SIMS in the event-by-event bombardment/detection mode. International Journal of Mass Spectrometry, 2011, 303, 97-102.	1.5	25
62	Single Impacts of C₆₀ on Solids: Emission of Electrons, Ions and Prospects for Surface Mapping. Journal of Physical Chemistry C, 2010, 114, 5637-5644.	3.1	27
63	Photon, Electron, and Secondary Ion Emission from Single C₆₀ keV Impacts. Journal of Physical Chemistry Letters, 2010, 1, 3510-3513.	4.6	8
64	Electron Emission from Hypervelocity C₆₀ Impacts. Journal of Physical Chemistry C, 2010, 114, 17191-17196.	3.1	8
65	Characterization of Individual Ag Nanoparticles and Their Chemical Environment. Analytical Chemistry, 2009, 81, 1089-1094.	6.5	20
66	Molecular Identification of Individual Nano-Objects. Analytical Chemistry, 2009, 81, 7527-7531.	6.5	13
67	Micropatterning of Proteins and Mammalian Cells on Indium Tin Oxide. ACS Applied Materials & Interfaces, 2009, 1, 2592-2601.	8.0	52
68	Emission of molecular fragments synthesized in hypervelocity nanoparticle impacts. International Journal of Mass Spectrometry, 2008, 275, 86-90.	1.5	11
69	Exercising Spatiotemporal Control of Cell Attachment with Optically Transparent Microelectrodes. Langmuir, 2008, 24, 6837-6844.	3.5	40
70	Secondary ion mass spectrometry with C60+ and Au4004+ projectiles: Depth and nature of secondary ion emission from multilayer assemblies. International Journal of Mass Spectrometry, 2008, 269, 112-117.	1.5	22
71	Characterization of Individual Nano-Objects by Secondary Ion Mass Spectrometry. Analytical Chemistry, 2008, 80, 9052-9057.	6.5	21
72	Examination of Nanoparticles via Single Large Cluster Impacts. Nano Letters, 2008, 8, 1076-1080.	9.1	17

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73	Prompt in situ emission of gold adducts from single impacts of large gold clusters on organics solids. International Journal of Mass Spectrometry, 2007, 263, 298-303.	1.5	14
74	Nanovolume Analysis with Secondary Ion Mass Spectrometry Using Massive Projectiles. Analytical Chemistry, 2006, 78, 7410-7416.	6.5	22
75	Influence of massive projectile size and energy on secondary ion yields from organic surfaces. Applied Surface Science, 2006, 252, 6529-6532.	6.1	17
76	Organic SIMS with single massive gold projectile: Ion yield enhancement by silver metallization. Applied Surface Science, 2006, 252, 6644-6647.	6.1	6
77	Molecular ion emission from single large cluster impacts. Applied Surface Science, 2006, 252, 6490-6493.	6.1	17
78	Matrix-enhanced cluster-SIMS. Applied Surface Science, 2006, 252, 6624-6627.	6.1	21
79	Au-analyte adducts resulting from single massive gold cluster impacts. Applied Surface Science, 2006, 252, 6558-6561.	6.1	10
80	Multiple secondary ion emission from keV massive gold projectile impacts. International Journal of Mass Spectrometry, 2005, 241, 57-61.	1.5	17
81	Multi-ion emission from large and massive keV cluster impacts. International Journal of Mass Spectrometry, 2005, 245, 48-52.	1.5	20
82	Coincidental emission of molecular ions from keV carbon cluster impacts. International Journal of Mass Spectrometry, 2004, 238, 59-64.	1.5	9
83	Cluster secondary ion mass spectrometry: an insight into â€œsuper-efficientâ€•collision cascades. Applied Surface Science, 2004, 231-232, 54-58.	6.1	13
84	Layer-by-layer characterization of ultrathin films with secondary ion mass spectrometry. Applied Surface Science, 2004, 231-232, 328-331.	6.1	8
85	Nanodomain analysis via coincidence ion mass spectrometry. Applied Surface Science, 2004, 231-232, 113-116.	6.1	5
86	Characterization of surface structure by cluster coincidental ion mass spectrometry. Applied Surface Science, 2004, 231-232, 106-112.	6.1	9
87	Surface Mass Spectrometry at the Submicrometer Scale. Langmuir, 2002, 18, 8836-8840.	3.5	14
88	A novel approach for coincidence ion mass spectrometry. Analytical and Bioanalytical Chemistry, 2002, 373, 609-611.	3.7	4
89	Effectiveness of atomic and polyatomic primary ions for organic secondary ion mass spectrometry. International Journal of Mass Spectrometry, 2001, 207, 111-122.	1.5	28
90	Secondary ion yield improvements for phosphated and sulfated molecules using substrate-enhanced time-of-flight secondary ion mass spectrometry. International Journal of Mass Spectrometry, 2001, 209, 113-124.	1.5	4

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91	Influence of constituent mass on secondary ion yield enhancements from polyatomic ion impacts on aminoethanethiol self-assembled monolayer surfaces. Rapid Communications in Mass Spectrometry, 2001, 15, 370-372.	1.5	4
92	Characterization of Photooxidized Self-Assembled Monolayers and Bilayers by Spontaneous Desorption Mass Spectrometry. Analytical Chemistry, 2000, 72, 5973-5980.	6.5	14
93	Secondary cluster ion emission from megaelectron volts ion impacts on NaBF4. 1. Ion decay fractions and dissociation pathways. International Journal of Mass Spectrometry, 2000, 202, 111-119.	1.5	4
94	Determination of the metastable dissociation pathways for chromium/oxygen cluster ions sputtered from potassium chromate and dichromate using the ion-neutral correlation method. International Journal of Mass Spectrometry, 2000, 203, 59-69.	1.5	8
95	Secondary ion emission from keV energy atomic and polyatomic projectile impacts on sodium iodate. International Journal of Mass Spectrometry, 2000, 197, 149-161.	1.5	13
96	SIMS of Organic Anions Adsorbed onto an Aminoethanethiol Self-Assembled Monolayer:Â An Approach for Enhanced Secondary Ion Emission. Analytical Chemistry, 2000, 72, 2618-2626.	6.5	13
97	Speciation of Sodium Nitrate and Sodium Nitrite Using Kiloelectronvolt Energy Atomic and Polyatomic and Megaelectronvolt Energy Atomic Projectiles with Secondary Ion Mass Spectrometry. Analytical Chemistry, 2000, 72, 2468-2474.	6.5	7
98	Carbon-cluster formation from polymers caused by MeV-ion impacts and keV-cluster-ion impacts. Physical Review A, 1999, 59, 4470-4474.	2.5	10
99	Secondary ion yields produced by keV atomic and polyatomic ion impacts on a self-assembled monolayer surface. , 1999, 13, 1374-1380.		26
100	Negative secondary ion emission from NaBF4 : comparison of atomic and polyatomic projectiles at different impact energies. Journal of Mass Spectrometry, 1999, 34, 554-562.	1.6	16
101	Calcium Phosphate Phase Identification Using XPS and Time-of-Flight Cluster SIMS. Analytical Chemistry, 1999, 71, 149-153.	6.5	191
102	Solidâ^'Liquid Adsorption of Calcium Phosphate on TiO2. Langmuir, 1999, 15, 7355-7360.	3.5	45
103	Sputtering of Tetrafluoro- and Tetraphenylborate Anions Adsorbed to an Amine-Terminated Self-Assembled Monolayer Surface. Journal of Physical Chemistry B, 1999, 103, 7929-7934.	2.6	8
104	Ionâ€“neutral correlations from the dissociation of metal oxide cluster ions in a reflectron time-of-flight mass spectrometer. Journal of Mass Spectrometry, 1999, 34, 677.	1.6	0
105	Sublinear effect in light emission from cesium iodide bombarded by keV polyatomic projectiles. Nuclear Instruments & Methods in Physics Research B, 1998, 134, 352-359.	1.4	6
106	Recoiled ions from polyatomic cluster impacts on organic and inorganic targets. Nuclear Instruments & Methods in Physics Research B, 1998, 142, 606-611.	1.4	5
107	Probing silicon substitution in molecular sieves by plasma desorption mass spectrometry. Journal of Molecular Structure, 1998, 470, 183-190.	3.6	0
108	Kiloelectron volt cluster impacts: prospects for cluster-SIMS. International Journal of Mass Spectrometry and Ion Processes, 1998, 174, 167-177.	1.8	48

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109	Multiplicity analysis: a study of secondary particle distribution and correlation. Surface Science, 1998, 408, 28-42.	1.9	12
110	An old-new tool for nuclear analysis: Time-of-Flight spectrometry. Journal of Radioanalytical and Nuclear Chemistry, 1997, 215, 23-30.	1.5	5
111	Matrix Effects on the Fragmentation of Vitamin B12 in Plasma Desorption Mass Spectrometry. Rapid Communications in Mass Spectrometry, 1997, 11, 143-147.	1.5	13
112	Time-of-flight-secondary ion mass spectrometry of NaBF4: a comparison of atomic and polyatomic primary ions at constant impact energy. Rapid Communications in Mass Spectrometry, 1997, 11, 1794-1798.	1.5	20
113	A plasma desorption mass spectrometry study of cluster ion formation from group IIA nitrates. Nuclear Instruments & Methods in Physics Research B, 1996, 112, 55-58.	1.4	3
114	The use of coincidence counting mass spectrometry to study the emission and metastable dissociation of cluster ions. Nuclear Instruments & Methods in Physics Research B, 1996, 112, 68-71.	1.4	5
115	Time-correlated luminescence from MeV projectile impacts. Nuclear Instruments & Methods in Physics Research B, 1996, 119, 583-586.	1.4	0
116	Secondary cluster ion distributions produced by MeV ion impacts on Group IIA oxides and nitrates. International Journal of Mass Spectrometry and Ion Processes, 1996, 155, 89-97.	1.8	5
117	Plasma desorption mass spectrometry of small straight-chain and cyclic alkenes. Journal of Mass Spectrometry, 1995, 30, 305-311.	1.6	2
118	A mass spectrometric method for probing surface structure. Vacuum, 1995, 46, 1227-1230.	3.5	4
119	A preliminary screening technique for selected metals at waste sites. Journal of Radioanalytical and Nuclear Chemistry, 1995, 192, 275-280.	1.5	7
120	Secondary ion correlations in plasma desorption mass spectrometry as a function of fission fragment energy. Nuclear Instruments & Methods in Physics Research B, 1995, 96, 536-540.	1.4	2
121	High energy chemistry caused by fast ion-solid interactions. Nuclear Instruments & Methods in Physics Research B, 1995, 96, 530-535.	1.4	13
122	Luminescence of self-trapped excitons induced by single keV ion bombardment. Nuclear Instruments & Methods in Physics Research B, 1995, 100, 383-388.	1.4	3
123	Solid-state luminescence: Probe for ion-solid interactions. Physical Review B, 1995, 51, 7373-7376.	3.2	9
124	Fragment ion formation fromn-alkanes and cycloalkanes by plasma desorption. Organic Mass Spectrometry, 1994, 29, 679-683.	1.3	5
125	Coincidence counting analysis of secondary ions emitted from a phenylalanine target under multicharged MeV carbon bombardment. International Journal of Mass Spectrometry and Ion Processes, 1994, 136, 107-117.	1.8	3
126	New approaches for neutron depth profiling. Journal of Radioanalytical and Nuclear Chemistry, 1994, 180, 255-262.	1.5	4

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127	Surface structure investigations using plasma desorption mass spectrometry and coincidence counting. International Journal of Mass Spectrometry and Ion Processes, 1993, 128, 133-141.	1.8	16
128	Interaction of atomic and molecular MeV ions with surface. Nuclear Instruments & Methods in Physics Research B, 1993, 79, 215-218.	1.4	2
129	Exit conditions for secondary ion emission induced by keV cluster bombardment. Nuclear Instruments & Methods in Physics Research B, 1993, 82, 317-322.	1.4	9
130	Studies in neutron depth profiling. Journal of Radioanalytical and Nuclear Chemistry, 1993, 167, 111-119.	1.5	3
131	Primary ion production from various gases in spontaneous desorption. International Journal of Mass Spectrometry and Ion Processes, 1993, 128, 107-113.	1.8	3
132	A coincidence counting study of spontaneous desorption. International Journal of Mass Spectrometry and Ion Processes, 1993, 127, 1-9.	1.8	2
133	Diffusion of lithium-6 isotopes in lithium aluminate ceramics using neutron depth profiling. Journal of Nuclear Materials, 1993, 203, 43-49.	2.7	6
134	A spontaneous desorptionâ€based polyatomic ion source. Review of Scientific Instruments, 1993, 64, 1748-1753.	1.3	7
135	Coincidence counting for the study of hydrocarbon ion desorption in plasma desorption mass spectrometry. Journal of Chemical Physics, 1992, 96, 3206-3210.	3.0	12
136	A coincidence counting study of polyatomic ion induced sputtering. Journal of Chemical Physics, 1992, 96, 8171-8176.	3.0	10
137	Analysis of polystyrene/PVME blends by coincidence counting time-of-flight mass spectrometry. Analytical Chemistry, 1992, 64, 843-847.	6.5	18
138	A brief review of the determination of cadmium by prompt gamma-ray neutron activation analysis. Journal of Radioanalytical and Nuclear Chemistry, 1991, 152, 497-506.	1.5	7
139	Impact of slow gold clusters on various solids: nonlinear effects in secondary ion emission. Nuclear Instruments & Methods in Physics Research B, 1991, 62, 8-22.	1.4	174
140	Surface analysis with keV polyatomic projectiles. Nuclear Instruments & Methods in Physics Research B, 1991, 56-57, 361-364.	1.4	6
141	Plasma desorption mass spectrometry with coincidence counting for the analysis of polymer surfaces. Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films, 1991, 9, 1300-1306.	2.1	6
142	Surface characterization with keV clusters and MeV ions. Nuclear Instruments & Methods in Physics Research B, 1990, 50, 307-313.	1.4	22
143	Cf-252 particle desorption mass spectrometry of photo-oxidized polystyrene. Surface and Interface Analysis, 1990, 15, 503-508.	1.8	5
144	Surface characterization of chemically modified chrysotile asbestos by particle-induced desorption mass spectrometry. Surface and Interface Analysis, 1990, 15, 651-658.	1.8	4

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145	Spontaneous desorption: field assisted ion induced desorption mass spectrometry. International Journal of Mass Spectrometry and Ion Processes, 1990, 97, 311-324.	1.8	8
146	Coincidence Counting in Time-of-Flight Mass Spectrometry: A Test for Chemical Microhomogeneity. Science, 1990, 248, 988-990.	12.6	57
147	A new experimental method for determining secondary ion yields from surfaces bombarded by complex heterogeneous ions. Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films, 1990, 8, 2265-2268.	2.1	16
148	Secondary-ion yields from surfaces bombarded with keV molecular and cluster ions. Physical Review Letters, 1989, 63, 1625-1628.	7.8	121
149	Multicomponent dye detection with californium-252 particle-desorption mass spectrometry. Analytica Chimica Acta, 1989, 218, 85-92.	5.4	2
150	Particle desorption mass spectrometry of Yî—¸Baî—¸Cuî—¸O superconductors. International Journal of Mass Spectrometry and Ion Processes, 1989, 91, R5-R11.	1.8	8
151	Advances in nuclear analysis methods. Analyst, The, 1989, 114, 269.	3.5	4
152	HYDROGEN IONS EMISSION UNDER FAST CHARGED PARTICLES : THE BEGINNING OF THE DESORPTION PROCESS. Journal De Physique Colloque, 1989, 50, C2-79-C2-84.	0.2	4
153	CLUSTERS AS PROJECTILES FOR SIMS. Journal De Physique Colloque, 1989, 50, C2-85-C2-92.	0.2	2
154	DESORPTION YIELDS USING keV POLYATOMIC PROJECTILES. Journal De Physique Colloque, 1989, 50, C2-147-C2-153.	0.2	1
155	Design and performance evaluation of a miniaturized particle desorption mass spectrometer. Nuclear Instruments and Methods in Physics Research, Section A: Accelerators, Spectrometers, Detectors and Associated Equipment, 1988, 273, 203-210.	1.6	6
156	X-ray photoelectron spectroscopy and Rutherford backscattering spectrometry study of anion incorporation in anodically grown films. Thin Solid Films, 1988, 167, 245-254.	1.8	5
157	A comparison of SIMS and PDMS: Analyses of mixed metal oxides. Materials Chemistry and Physics, 1988, 20, 485-499.	4.0	2
158	252Cf-particle desorption mass spectrometry in a depth profiling mode. Nuclear Instruments & Methods in Physics Research B, 1988, 34, 89-96.	1.4	8
159	Methodology and application of the nuclear resonance reaction 16O(Î±, Î±)16O for the profiling of titanium oxide. Nuclear Instruments & Methods in Physics Research B, 1988, 35, 159-166.	1.4	34
160	Surface characterization of a National Bureau of Standards glass reference material by californium-252 particle desorption mass spectrometry. Analytical Chemistry, 1988, 60, 1944-1947.	6.5	3
161	Fingerprinting of polymer surfaces with Cfâ€252 particle desorption mass spectrometry. Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films, 1988, 6, 946-949.	2.1	10
162	On the origin of hydrogen clusters produced by particle induced desorption. Journal of Chemical Physics, 1988, 89, 6708-6712.	3.0	14

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163	Micro and surface analysis with fast heavy ions. Analytica Chimica Acta, 1987, 195, 163-172.	5.4	7
164	Recent developments in chemical characterization with MeV ion beams. Journal of Radioanalytical and Nuclear Chemistry, 1987, 110, 451-460.	1.5	2
165	Studies in heavy ion activation analysis trace determination possibilities with9Be bombardment. Journal of Radioanalytical and Nuclear Chemistry, 1987, 116, 401-408.	1.5	1
166	Trace determination of lead by helium-4 activation analysis. Journal of Radioanalytical and Nuclear Chemistry, 1987, 119, 81-86.	1.5	4
167	Compact timeâ€ofâ€flight mass spectrometer using particleâ€induced desorption. Review of Scientific Instruments, 1986, 57, 692-694.	1.3	23
168	Application of particle desorption mass spectrometry to the characterization of minerals. Analytical Chemistry, 1986, 58, 2126-2129.	6.5	3
169	Particle induced desorption mass spectrometry in a microscopic mode. Analytical Chemistry, 1986, 58, 1686-1690.	6.5	5
170	Trace determination of rhodium using proton activation followed by X-ray counting. Journal of Radioanalytical and Nuclear Chemistry, 1986, 100, 197-201.	1.5	2
171	Ion-induced desorption in insulators by Hydrogen cluster impact up to 600 KeV. Radiation Effects, 1986, 99, 213-226.	0.4	5
172	On the determination of phosphorus via charged particle activation analysis. Journal of Radioanalytical and Nuclear Chemistry, 1985, 91, 173-178.	1.5	8
173	Studies in heavy ion activation analysis. Journal of Radioanalytical and Nuclear Chemistry, 1985, 88, 369-377.	1.5	4
174	Characterization of tantalum pentoxide films with backscattering spectrometry. Journal of Radioanalytical and Nuclear Chemistry, 1985, 90, 325-332.	1.5	0
175	Studies in heavy ion activation analysis. Journal of Radioanalytical and Nuclear Chemistry, 1985, 90, 341-348.	1.5	6
176	Studies in heavy ion activation analysis. Journal of Radioanalytical and Nuclear Chemistry, 1985, 90, 349-354.	1.5	1
177	Desorption mass spectrometry using cluster ions. Nuclear Instruments & Methods in Physics Research B, 1985, 10-11, 751-753.	1.4	0
178	On the determination of carbon and oxygen impurities in silicon by3He activation analysis. Journal of Radioanalytical and Nuclear Chemistry, 1984, 81, 125-129.	1.5	10
179	The unusual structure of tungsten-doped electrochemically-grown alumina films detected by MeV ion scattering. Journal of the Chemical Society Chemical Communications, 1984, , 1560.	2.0	3
180	Rutherford backscattering with heavy ions. Journal of Radioanalytical Chemistry, 1983, 78, 181-187.	0.5	0

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181	Radioactive implant induced X-ray emission: Part II. Nuclear Instruments & Methods in Physics Research, 1983, 216, 497-500.	0.9	1
182	Spatially resolved heavy ion induced desorption mass spectrometry. International Journal of Mass Spectrometry and Ion Physics, 1983, 53, 331-334.	1.3	5
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